

4-point probe head

➔ 4-point probe head Cartridge type, Cylindrical type, Miniature type, Cartridge with 6-way connector socket type

① Cartridge type (Napson original)



③ 6-way connector socket type



② Miniature type



④ Cylindrical type



Selling Points

Napson 4-point resistivity / sheet resistance systems are using high performance probe heads which are made by Jandel Engineering Limited of England.

Jandel probe head performs high precise measurement of resistivity and sheet resistance for silicon wafers, epitaxial layers, diffusion layers, ITO layers, metal layers and more, so that Jandel probes have a good evaluation for many years.

*Load (needle pressure) is always suitable since using V type spring
 *Probe spacing accuracy and probe stability is excellent since anodized aluminum alloy upper and lower guides are jeweled
 *Less damage of probe needle tips - Solid tungsten carbide needles for superior durability

Details

Applications

The probe type is chosen under the material of measuring sample, the surface state, the form etc.

Measurement sample	Probe head (Material/Radius)	Load/Needle
Silicon Ingots / Block	TC-40μ	200g
Silicon Slice	TC-40μ	200g
Epitaxial Layers	TC-150μ	100g
Epitaxial Layers (Thin film)	TC-150μ, 500μ	50g
Shallow Diffused Layers (Thin film)	OS-200μ, 500μ	50g
Diffused Layers	OS-200μ, TC-150μ	100g
Ion Implantation	TC-150μ	50g, 100g
Metal (Thin film)	TC-150μ, 500μ	10g, 50g, 100g
ITO layer	TC-150μ, 500μ	10g, 50g, 100g

*The other types are available.

*If you would like to have a special spec, contact us.

<Specifications>

e.g) TC-40μ-200g/1.00mm

- Needle Material: TC (Tungsten carbide) (or OS: Osmium alloy)

- Radius: 40 μm (25 μm to 500 μm)

- Loads (g/needle): 200g (10g to 250g)

- Spacing: 1.00 mm (0.5 mm to 1.59 mm)

- Arrangement: Linear (standard) (Square is available)